28th RD50 Workshop (Torino)



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ESR of point defects in pure and 17O/13C doped Si-FZ irradiated with 3.5 and 27 MeV electrons. Correlation with TSC data.

Wednesday, 8 June 2016 09:20 (20 minutes)

Presenter: Dr NISTOR, Vasile Sergiu (National Institute of Materials Physics)

Session Classification: Radiation Damage I